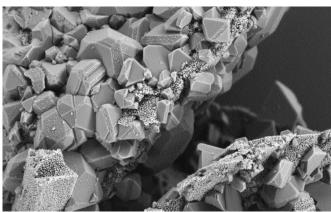
## **Increased productivity**

# with improved image quality

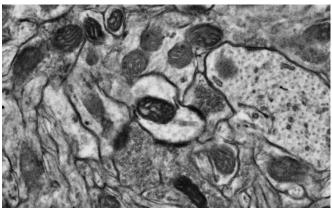
### **ZEISS AsB Detector**

Increase productivity and improve the image quality of your FE-SEM by retrofitting the new Angle selective Backscattered (AsB) Detector. Benefit from high speed and increased sensitivity thanks to improved detector and electronic design.

The new detector builds on the proven detection scheme of AsB with a new low kV capable detector diode, already known from MERLIN systems.



Fe<sub>2</sub>O<sub>2</sub>+ ZrO analysis, imaged with AsB Detector.



Rat brain thin section, imaged with AsB Detector.

#### **Highlights**

#### Improved material contrast

Depict a lot of different contrast mechanisms with the segmented detection diode and the flexible mixing of signals

#### Low-kV imaging

Reduce energy and benefit from enhanced image quality

#### Steady temperature level

Rely on high long-term and temperature stability for particle scanning

#### **Upgrade your ZEISS microscope**

Upgrade your ZEISS microscope with the AsB Detector option and benefit from better and faster imaging and temperature stability.

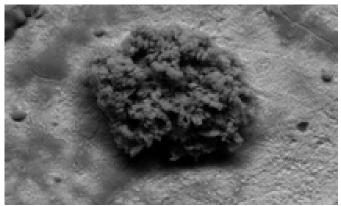
As technical requirements may apply on some systems, please contact us to learn more about the AsB Detector and how your processes will benefit from an upgrade: microscopy@zeiss.com



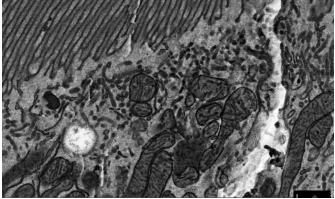
Seeing beyond

### **ZEISS AsB Detetcor**

## Improved image quality



Surface deposition on silicon, imaged with AsB Detector.



Apex of rat kidney epithelium cells showing micro-villi and numerous mitochondria, imaged with ASB Detector.

#### **Availability**

- GeminiSEM series
- SUPRA series
- MERLIN series
- ULTRA series
- 15xx series

#### Ease of use

- Complete integration into the pole piece, no need to move in and out
- Plug and play technology
- No alignment to the optical axis necessary
- Safe Navigation option prevents samples and stage from damaging the detector
- Seamless integration of software packages (e.g. SmartPI) in the work-flow